

Trusted Computing Engineering For Resource Constrained Embedded Systems Applications

Identification of Requirements

D2.2 Requirements Application Viewpoint

D3.1 Requirements Engineering Viewpoint

D4.1 Requirements on Repository

Project: TERESA Project Number: IST-248410

Deliverable: D2.2, D3.1 and D4.1

Title: Identification of Requirements for WP2, WP3 and WP4

v1.0

Confidentiality: Public
Author: All partners
Date: 3 December 2010

Version:

SEVENTH FRAMEWORK PROGRAMME

Part of the Seventh Framework Programme Funded by the EC - DG INFSO



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1 Document History

Version	Status	Date
v0.1	draft	28/04/2010
V0.2	Adding the vision of Teresa and the conceptual model	21/09/2010
V0.3	Restructuring requirements	22/09/2010
V0.4	Adding the vision of Teresa	24/09/2010
V0.5	Modifying requirements during the trilateral meeting	27/09/10
V0.6	Reorganising and correcting requirements	15/10/10
V0.7	Reorganising the requirements	02/11/10
V1.0	Taking into account comments from the cross-checking	12/11/10

Approval						
	Name		Date			
Prepared	All Project Partners		02 11 2010			
Reviewed	Andreas Fuchs, Annika Paus		08 11 2010			
Authorised	Antonio Kung		03 12 2010			
Circulation	Circulation					
Recipient		Date of submission				
Project partners		03 12 2010				
European Commission		03 12 2010				



2 Executive Summary

This document addresses the set of requirements involved in the TERESA process and represents the deliverables D2.2, D3.1 & D4.1. As a first step for the identification of the requirements, the document gives an overview of the vision of the TERESA project in order to show the restrictions to be faced (RCES, S&D properties) and the strategies to follow (MDE, process sub-division) to handle this issues. Moreover, a brief overview is provided of the TERESA conceptual model to illustrate the context and to have a common understanding of the concepts used in this deliverable.

Once the context of the TERESA process is described, a description of each identified requirement is defined. These requirements are mainly focused on the viewpoint of engineering process definition in order to develop pattern-based applications (define, integrate, transform, and validate a pattern in an application). In addition, the document identifies ways in which the engineering process may serve the engineer in the implementation of this process, and finally, it identifies the restrictions that have to be considered in the definition of the repository.

For clarity, the requirements have been structured in three main sub-processes that are directly related with the main actions the engineering process supports, which are *Pattern Life Cycle process*, *Integration Process Transformation* and *Repository Structure*.



3 Acronyms

Acronym	Meaning			
HW	Hardware			
MDE	Model Driven Engineering			
PIM	Platform Independent Model			
PSM	Platform Specific Model			
RCES	S Resource Constrained Embedded Systems			
SW	Software			



4 Introduction

The main purpose of this document is to identify requirements related to TERESA concerns. This document corresponds to the deliverables D2.2 Requirements Application Viewpoint, D3.1 Requirements Engineering Viewpoint and D4.1 Requirements on Repository. Section 4.1 gives a detailed description of the vision of TERESA, Section 4.2 introduces the TERESA conceptual model. Section 4.3 deals with the organization of the document and highlights why all deliverables are merged in one document.

4.1 The Vision of the TERESA Project

Embedded systems correspond to information processing systems integrating HW and SW embedded into enclosing products to fulfil a specific function. This kind of system is referred to RCES (Resource Constrained Embedded Systems) if they have memory, autonomy, and/or computation processing restrictions. The industry is friendly to manage RCES with time and computation constraints. Although the issue is complex, solutions exist.

Currently, security and dependability (S&D) becomes a strong requirement. In many industries, this need is reflected in changing their processes to integrate this new business. As shown in Figure 1, during the RCES development, many engineering roles have to be considered. A clear separation of these roles is required while ensuring the coherence and the consistency between them.

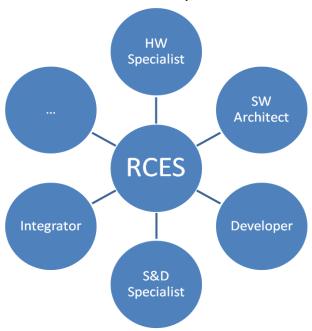


Figure 1: Synergy of all stakeholders

Model Driven Engineering (MDE) can provide some solutions for this issue. A model provides an abstraction of specific views of the system. For each concern, a specific view can be developed. For RCES, some MDE-based initiatives already exist like the MARTE UML profile [1].

In MDE, as depicted in Figure 2, the global process distinguishes two levels:

- PIM Platform Independent Model. A PIM is a model that is independent of any platform (i.e., at the HW & SW levels) and doesn't contain information on technologies that will be used to deploy the application. At the start, this model is independent of the domain. Then, during the refinement of the model, domain specific concepts are introduced.
- PSM Platform Specific Model. This model shows the details of the platform. The PSM is essentially the basis for executable code loaded on the platform. There are several levels of PSM. The first is the result of the transformation of a PIM. It may be represented using UML diagrams related to a specific platform. Other PSMs are obtained using successive transformations until the code generation in a specific language (i.e., C, Java, C #, etc). In this case, a PSM contains information such as program code, related libraries and descriptors of deployment.

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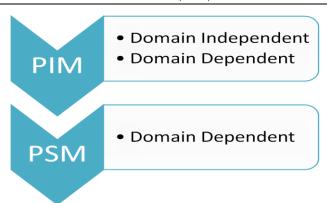


Figure 2: OMG MDE-based product process

S&D requirements can be fulfilled by several solutions. These solutions are often reused in several projects and can be represented by a pattern. A pattern is like a template which responses to a specific issue. Patterns can be stored into a repository and then, they can be reused at the development time. For this purpose, it is necessary to search in the repository a pattern which meets the application requirements. By consequence, the use of patterns can ease the integration of one of these solutions due to reusability. However, this technique has an impact on the engineering process which needs to be completely redesigned to efficiently support the pattern paradigm.

In TERESA, we focus on pattern-based application development. As depicted in Figure 3, several kinds of processes are needed. Note that the product process (i.e., application development process) is ignored in Figure 3.

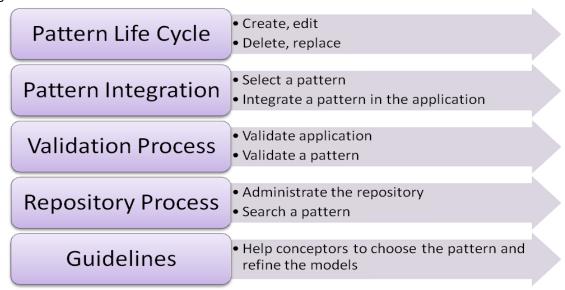


Figure 3: Main processes in a pattern-based application development

The *Pattern Life Cycle process* corresponds to all the tasks related to the pattern development (to create, to update, to delete, etc). At the end, the pattern is stored in a repository.

The goal of *Pattern Integration process* consists to plug a pattern in an application. For this purpose, in function of S&D properties, the security engineer can require all patterns stored in the repository which meet his needs. Then, through model transformations, the pattern is integrated in the application model.

The *Validation process* is transversal and interacts with the pattern life cycle and pattern integration processes. At each step of these processes, it is possible to validate a pattern or an application from an S&D point of view.

The *Repository process* manages the pattern repository and provides a pattern search mechanism.

At last, **Guidelines** are needed in order to help designers during the pattern life cycle and pattern integration processes.



As depicted in Figure 4, the TERESA vision consists in application development by pattern construction. The TERESA vision is based on two main processes centralised around a repository. The repository provides S&D patterns which can be used during the application development. In order to design patterns, some guidelines help the security specialists. At the end of the pattern development, formal validation guarantees that the pattern achieves the required S&D properties.

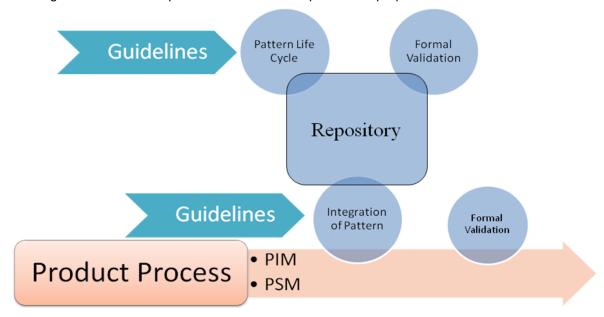


Figure 4: The TERESA Vision

Currently, the state of the art covers some parts of this global process for specific issues. However, there is no solution which provides an S&D pattern repository, guidelines and uses model driven engineering.

4.2 The TERESA Conceptual Model

In this section, we present the TERESA conceptual model. The goal of this model is to illustrate the addressed problems and to have a common understanding of all the concepts used in this deliverable. In the following text, all concepts are typeset in bold letters at the moment of their definition. The TERESA conceptual model is composed in four models presented in the following sections. The goal of this conceptual model is to define the different notions used in TERESA.

4.2.1 The Fault Propagation Model

A system is a combination of interacting elements organized to achieve one more stated purposes. [2] In TERESA, we make use of this model to comprehend all the factors that may lead to an error of an embedded system and hence to determine the trust level of a system. Here, we mainly focus on RCES. Basically, the trust level of a system decreases if a fault could damage the system. Typically, a fault can have a direct influence on S&D. Generally, the AVI (Attack, Vulnerability, and Intrusion) fault model is used to demonstrate the $fault \rightarrow error \rightarrow failure$ paradigm (see the Figure 5) [3]. Figure 5 explains how a fault could be propagated into the system and how it could lead to a failure.

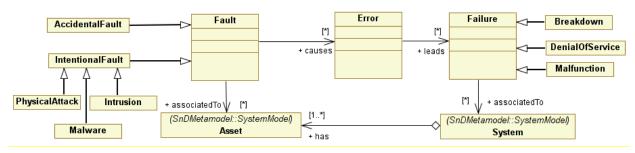


Figure 5: Fault Propagation Model



As shown in Figure 5, a **fault** is the presumed or hypothesized cause of an **error**. Faults may be classified according to several criterions. A fault is related to an asset of the system. An asset could be hardware, software, people, etc... Here, we classify faults as **accidental** or **intentional**. Accidental faults can arise during either the system design and development process or during operation (through a violation of an operating or maintenance procedure).

Intentional faults fall into three classes: **malware**, **physical attacks** and **intrusions**. Typically an attack exploits a fault or vulnerability of an **asset** to make an intrusion. An attack may use physical means to cause faults, such as power fluctuations, radiation, or wire-tapping. [4]

An error is detected if its presence in the system triggers an error message or error signal that originates from within the system. The possibility to detect errors contributes to improved security and trust in the system. Errors that are present but not detected are called latent errors. In [5], Avizenis defines an error as the part of the system state that may lead to a **failure**.

A failure leads to the inability of the system or some of its parts to meet their specifications (functional and non-functional requirements). Possible failures could be: **breakdown**, **denial of service** and **malfunction**.

4.2.2 The Trust Model

In order to limit the probability of occurrence as well as the impact of a fault, TERESA uses a Trust Model, depicted in Figure 6, to visualize the dependencies of a RCES's trust that is built on a number of factors.

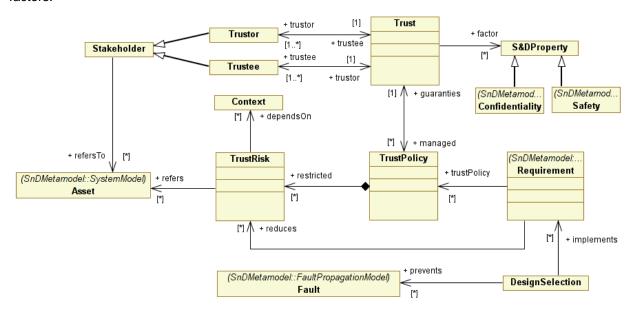


Figure 6: Trust Model

As depicted in Figure 6, a **trustor** can trust a **trustee** if, and only if, at least one factor of S&D is guaranteed (these factors are called **S&D Property** in Figure 6). For this reason, during the development process, requirement identification is a main issue. [6] In order to fulfil the **requirements**, it is possible to define **policies** which enforce the trust level. Then, during the system implementation, **design selection** will implement the requirements and reduces the **risk of fault**.

4.2.3 The S&D Properties Model

While the Trust Model in Figure 6 figures out that trust is related to several factors or dimensions [7], the model in Figure 7 summarizes possible criteria in S&D. It shows, for instance, that a user could trust a system because it is confidentiality-aware and will protect his personal data. Of course, it is needed that design selections implement mechanisms which ensure this quality of service (i.e., access control, anonymity, non-repudiation, etc).



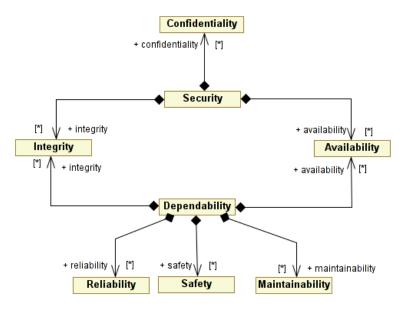


Figure 7: S&D Properties

4.2.4 The Pattern and Artefact Model

In the TERESA project, different application sectors are considered. Each sector has its own needs and constraints for the development of its applications. In TERESA we adapt the application through the use of patterns in order to handle these needs and constraints. As shown in Figure 8, applications can be composed of different patterns.

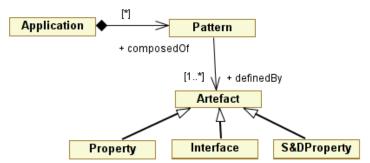


Figure 8: Pattern & Artefact definition

At the same time, the patterns need a set of artefacts such as interfaces, attributes, internal structure, and others that support the description of the features/qualities that the pattern provides.

An artefact is a substance or structure not naturally present in the matter being observed but formed by artificial means. [8] In computer science, an artefact is an artificial product or effect observed in a natural system, especially one introduced by the technology used in scientific investigation. It allows creating something to represent every thing as a nonexistent entity in the field. That is, an artefact is something viewed as a product of human conception rather than an inherent element. For instance, a relevant artefact for embedded systems is time or resource constraint.



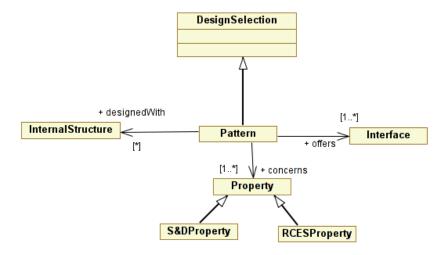


Figure 9: Pattern Structure

As shown in Figure 9, the pattern must address the features of the design selection through the adaptation of design features or by means of including extra features in order to take into account the concern properties (S&D properties, RCES properties) in the design.

Furthermore, to support the definition of the pattern and its integration in the design, the pattern is provided with a description of its internal structure and interfaces offered to communicate with the rest of the system.

4.3 Organization of the Document

The work plan of the TERESA project consists of several technical work packages (WP). For all of these WPs, a task consists of specifying the requirements. In the following text, a summary of this task is given:

- T2.2: the objective of this task is to identify the requirements of the trusted engineering process, from the engineer viewpoint. These requirements will be worked out in parallel with the requirements of WP3, which identify requirements from an engineering process viewpoint. Examples of domain specific requirements are standards and assurance approaches.
- T3.1: the objective of this task is to identify the requirements from an engineering process definition viewpoint. While the requirements from WP2 take a black box approach (i.e. what the engineering process should do to serve the engineer), the requirements in WP3 take an implementation approach (i.e. how the engineering process should be structured and constructed to serve WP2). For the definition of the requirements at the process level, it is important to take the domain specific requirements (e.g. existing standards for engineering) into account here.
- T4.1: the objective of this task is to specify and develop the repository that will be used to store the meta-models (engineering and trust meta-models), models (engineering process model, trust models, patterns models). The requirements for such repository will first be identified (e.g. administration, interoperability with other tools, format...)

For each task, a deliverable describes the respective requirements. Finally, the TERESA partners decided to write one document for all of them. The advantages of this process are to avoid redundant requirements and to allow the partners being involved in the requirement identification. However, the organization of this document highlights the work in each task.

A common organization of the requirements, presented in Section 5, 6, and 7, is used for each identified process. The first section describes the requirements at a conceptual level (relevant to T3.1 or T4.1 with respect to the target process). Then, a section specifies requirements relevant for the final user (i.e., T2.2).



5 Requirements on Pattern Lifecycle

In this section, we will identify and detail all requirements related to the pattern life cycle. This section is divided in two subsections. The first one, called "Conceptual Level", is relevant for the task 4.1 and represents a part of the deliverable D4.1. The second one, titled "Modelling Level" corresponds to the deliverable D2.2.

5.1 Conceptual Level

5.1.1 Artefacts

5.1.1.1 Unified S&D Artefact Ontology

REQ-PL-	001	Unified S&D ar	tefact ontology			
Description: In the process of pattern definition, a unified representation of the concepts to be used in the identification and definition of the S&D artefacts must be established.						
Source: General						
Reference process:	Pattern Life cycl	е				
	Rational: To establish a common understanding and also to identify different kind of artefacts that can be used for the definition of the pattern.					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4			
Date: 23/08/10			Version: 1.0			

5.1.1.2 Unified S&D Integration Requirements Artefact Ontology

REQ-PL-	002	Unified S&D in ontology	tegration requirements			
Description: In the process of pattern definition, a unified formal representation of the concepts to be used in the identification and definition of the S&D integration requirements must be established.						
Source: General						
Reference process:	Pattern Life cycl	е				
		_	also to identify different kind of on of the S&D integration			
Type: Mandatory Validation criteria: Inspection WP Relevance: 4						
Date: 07/06/10			Version: 1.0			



5.1.1.3 Unified S&D Formal Validation Artefact Ontology

PEN-PL-NN3	Unified S&D formal validation artefact ontology
• • • • • • • • • • • • • • • • • • • •	n description, a unified formal representation of

Description: In the process of pattern description, a unified formal representation of the concepts to be used in the identification and definition of the S&D formal validation artefacts must be established.

Source: General

Reference process: Pattern Life cycle

Rational: To establish a common understanding and also to identify different kind of concepts that can be used for the definition of the S&D formal validation artefacts.

Type: Mandatory Validation criteria: Inspection WP Relevance: 4

Date: 27/09/10 Version: 1.0

5.1.1.4 Pattern Integration Constraints

RF()-P1 -0104			rn integration traints/recom		

Description: In the application development, some recommendations or constraints have to be taken into account before integrating the pattern in the application. The developer needs this information available in the pattern description. This information that the pattern may require (i.e., resources, protocols, architecture, implementation techniques, etc) must be specified.

Source: General

Reference process: Pattern Lifecycle

Rational: To support the developer in the integration of the pattern

Type: Mandatory Validation criteria: Inspection WP Relevance: 4

Date: 31/08/10 **Version:** 1.0



5.1.1.5 Artefacts for Internal Structure Description

REQ-PL-	005	Artefacts for in	ternal structure description		
Description: In the process of pattern description, the internal structure of the pattern has to be defined. For this purpose, artefacts which are needed to describe the internal structure must be available.					
Source: General					
Reference process:	Pattern Life cycl	е			
Rational: To support the description of the pattern's internal structure.					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4		
Date: 07/06/10			Version: 1.0		

5.1.1.6 Artefacts for Interfaces

REQ-PL-	006	Artefacts for in	nterfaces			
Description: In the process of pattern description, the pattern's interfaces necessary to communicate with the rest of the design have to be defined. To this end, the artefacts needed to describe the interfaces must be available.						
Source: General						
Reference process:	Pattern Life cycl	e				
Rational: To support	Rational: To support the definition of the pattern's interfaces.					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4			
Date: 27/09/10			Version: 1.0			



5.1.1.7 Artefacts for Attributes

REQ-PL-	-007	Artefacts for a	ttributes	
Description: In the process of pattern description, the attributes (e.g. S&D properties) of the pattern have to be defined. To this end, the artefacts needed to describe the attributes must be available.				
Source: General	Source: General			
Reference process:	Reference process: Pattern Life cycle			
Rational: To support the definition of the attributes of the pattern.				
Type: Mandatory Validation criteria: Inspection WP Relevance: 4				
Date: 10/11/10 Version: 1.			Version: 1.0	

5.1.1.8 Variability of Artefact

REQ-PL-	-008	Variability of a	rtefacts	
Description: To be applicable in many domains, the process must support the variability of the pattern. Therefore, the artefacts required to define the pattern must be configurable or adaptable.				
Source: General				
Reference process:	Reference process: Pattern Life cycle			
Rational: To support the use and adaptation of the pattern to different application domains.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4	
Date: 07/06/10	•		Version: 1.0	



5.1.1.9 Extendibility of Existing Artefacts

REQ-PL-009 Extendibility of existing artefacts					
Description: Sometimes, the set of artefacts used to describe and to support the definition of the pattern are not enough. If a gap in the pattern definition is detected, the existing artefacts must be extensible to support the complete definition of the pattern.					
Source: General					
Reference process: Pattern Life cycle					
Rational: To allow extensibility of artefact for new necessities					
Type: Desirable Validation criteria: Inspection WP Relevance: 4					
Date: 31/08/10	1		Version: 1.0		

5.1.1.10 Extendibility of the Set of Artefacts

REQ-PL-	·010	Extendibility of	f the set of artefacts	
Description: If there are no artefacts available, that support the required needs, the process must support the creation and the integration of new artefacts.				
Source: General				
Reference process:	Pattern Life cycl	e		
Rational: To take into account and to express the new artefacts needed for describing a pattern.				
Type: Mandatory				
Date: 07/06/10			Version: 1.0	



5.1.2 Models

5.1.2.1 Role based Specification (Pattern S&D Expert, Formal Validation, Domain Integrator)

REQ-PL-	011	Role based Sp	ecification	
Description: In the process of pattern description, roles that interact with the pattern in the different phases of the application development must be taken into account in pattern specification.				
Source: General				
Reference process:	Reference process: Pattern Life cycle			
Rational: To identify the roles that interacts with the pattern at an early phase of pattern specification.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4	
Date: 07/06/10			Version: 1.0	

5.1.2.2 Top-down Multi-level Specification (Domain Independent, Domain Dependent Platform Independent, Domain Dependent Platform Specific)

		-		
REQ-PL-012 Top-down Multi-level Specification				
Description: In the process of pattern description it is advisable to follow a design approach in which the level of detail used in the description of the pattern is ever-increasing. For that reason, the specification of the pattern must be performed from a high level description to a detailed level description.				
Source: Industrial Control / Dependab	ility			
Reference process: Pattern Lifecycle				
Rational: To ease the comprehension of the pattern description.				
Type: • Mandatory for Industrial Control • Optional for other domains Validation criteria: Inspection/Test WP Relevance: 4				
Date: 07/06/10		Version: 1.0		



5.1.2.3 Role based and Level based Pattern Representation

RFQ-PI -013	Role based and Level based Pattern representation
behaviour of the pattern. The process the pattern representation and a description	we been defined to model the structure and the smust provide a list of necessary diagrams for cription of the approach chosen to apply them in divil wary according to the context in which it will

Role based and Level based Pattern

Source: General

Reference process: Pattern Life cycle

Rational: To identify and establish a sequence of the diagrams depending on the

context.

Validation criteria: Inspection Type: Mandatory WP Relevance: 4

Date: 27/05/10 Version: 1.0

5.1.2.4 Portability

REQ-PL-	014	Portability		
Description: In the process of pattern definition, the specification of the pattern must be platform-independent such that the pattern can be rebuilt for a new platform, without affecting any other pattern.				
Source: General				
Reference process:	Reference process: Pattern Life cycle			
Rational: To ease the portability of the pattern to different kinds of platform.				
Type: Mandatory	Validation criteria: Inspection WP Relevance: 4			
Date : 01/09/10		Version: 1.0		



5.1.2.5 Reusability

REQ-PL-	015	Reusability			
Description: The patterns are designed primarily to be reused in different applications. For that reason, the pattern developer must be aware of the needed artefacts which must be described. A pattern has to be as flexible as possible.					
Source: General					
Reference process:	Reference process: Pattern Life cycle				
Rational: To ease the reusability of the pattern in different domains					
Type: Mandatory Validation criteria: Inspection WP Relevance: 4					
Date : 01/09/10			Version: 1	.0	

5.1.2.6 Availability of Needed Artefacts Per Role and Per Level

REQ-PL-	016	Availability of I	needed artefacts per role/level	
Description: A set of artefacts have been identified to support the pattern description. The process must provide a list of artefacts. These must be organized in such a way that takes into account both the roles involved in the pattern's design process, as the pattern's design level where the artefacts will be used.				
Source: General				
Reference process:	Reference process: Pattern Life cycle			
Rational: To ease the identification of the artefacts required for defining a pattern.				
Type: Mandatory Validation criteria: Inspection WP Relevance: 4				
Date: 07/06/10 Version: 1.0				



5.1.2.7 Detailed Description of Patterns Internal Behaviour

REQ-PL-	017	Detailed Descr Behaviour	iption of Patterns Internal
Description: A pattern must be described in a sufficient level of detail that allows for the formalization and formal validation of its provided properties under the assumption of its required properties.			
Source: General			
Reference process: Pattern Life cycle			
Rational: To have a sufficient description level for using formal validation.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4
Date: 27/05/10	•		Version: 1.0

5.1.3 Transformations

5.1.3.1 Traceability of Artefacts During the Pattern Life Cycle

REQ-PL-	018	Traceability of life cycle	artefacts during the pattern
Description: In the pattern development different artefacts are required for the description of the pattern. The process must provide a mechanism to trace the changes made to the artefacts through the pattern development process.			
Source: General			
Reference process: Pattern Life cycle			
Rational: To trace the different artefacts used in the pattern definition			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4
Date: 07/06/10	•		Version: 1.0



5.1.3.2 Traceability of Properties Mechanism

REQ-PL-	properties during mechanism		
Description: In the pattern design process, it is necessary to check that properties identified in early stages are adequately implemented in later stages. The process must provide a mechanism to trace these properties through the pattern life cycle.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: To trace the properties implementation throughout the pattern definition.			
Type: Mandatory Validation criteria: Inspection WP Relevance: 4			WP Relevance: 4
Date: 27/05/10			Version: 1.0

5.1.3.3 Consistency between Pattern Levels

REQ-PL-020 Consistency between pattern levels				
Description: In order to develop a pattern, different levels to design the pattern have been identified. Throughout the development of these levels, the pattern is involved in a set of transformations. The process must ensure consistency between these transformations during the pattern design.				
Source: General				
Reference process: Pattern Lifecycle				
Rational: To maintain the consistency during pattern design.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4	
Date: 27/05/10 Version: 1.0				



5.1.3.4 Guidelines for Easy Pattern Definition

REQ-PL-021 Guidelines for easy pattern definition					
Description: In addition to the diagrams used for pattern description, a specific set of activities has to be carried out for pattern definition. For that reason, the set of actions (procedures) that form the pattern design process must be identified and organized to allow the pattern developer to carry out the pattern design in a clear and precise way.					
Source: Industrial Control / Dependability					
Reference process: Pattern Life cycle					
Rational: To establish a process in which the pattern developer can find the main steps and actions to carry out for pattern definition.					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4		

Version: 1.0

5.2 Modelling Level

Date: 27/05/10

5.2.1 Editable Artefacts

5.2.1.1 Pattern Properties

REQ-PL-	022	Pattern Proper	ties
Description: In the process of pattern description, the set of properties (e.g. dependability, security, RCES, quality, specific context) provided by the pattern must be specified.			
Source: General	Source: General		
Reference process: Pattern Lifecycle			
Rational: To easy the classification and selection of the pattern.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/09/10			Version: 1.0



5.2.1.2 Expressiveness of S&D Property Definition

REQ-PL-	023	Expressivenes	ss of S&D property definition	
Description: In the process of pattern definition, the S&D properties that are addressed by the pattern must be described in certain ways that they are precise, clear and easy to understand.				
Source: General				
Reference process: Pattern Lifecycle				
Rational: To easily understand the meaning of the S&D properties.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2	
Date: 27/09/10			Version: 1.0	

5.2.1.3 Pattern Integration Constraints/Recommendations

REQ-PL-	024	Pattern integra constraints/red	ntion commendations	
Description: In the application development, some recommendations or constraints have to be taken into account before integrating the pattern in the application. The developer needs this information available in the pattern description. This information that the pattern may require (i.e., resources, protocols, architecture, implementation techniques, etc) must be specified. In some cases the constraints available may vary in a pre-defined range in order to support the adaptability of the pattern.				
Source: General				
Reference process: Pattern Lifecycle				
Rational: To support the developer in the integration of the pattern				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2	
Date: 31/08/10		Date: 31/08/10 Version: 1.0		



5.2.1.4 Validation Constraints

REQ-PL-	025	Validation Con	straints
Description: At the end of the pattern integration process, the integration must be validated in order to check that the provided functionality has been reached. The constraints to be considered (related to the pattern) in the pattern validation process must be available.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: To identify the restrictions to take into account in the pattern validation process.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2

Version: 1.0

5.2.1.5 Repository Search Keys

Date: 27/09/10

REQ-PL-026 Repository Search Keys			
Description: In the pattern definition process, information relevant to the description of the pattern has been defined. Keywords that can help in the search of patterns must be available.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: To ease the search of the patterns.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/05/10	•		Version: 1.0



Type: Mandatory

Date: 31/08/10

5.2.1.6 Adaptable Pattern Description According to Role

	ng to			
Description: In the process of pattern integration, the function or set of functions that the pattern is able to provide must be available. The set of functions provided must vary according to the role of the person using the pattern. Source: General				
Reference process: Pattern Lifecycle				
Rational: In order to ease the identification and selection of the pattern in the repository.	· ·			

WP Relevance: 2

Version: 1.0

Validation criteria: Inspection

5.2.1.7 Adaptable Pattern Description According to Level

REQ-PL-	.117X	Adaptable Patt Level	ern Description According to
Description: In the process of pattern integration, function or set of functions that the pattern is able to provide must be available. The set of functions provided must vary according to the level where the pattern is used.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: In order to ease the identification and selection of the pattern in the repository.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/09/10	•		Version: 1.0



5.2.1.8 Adaptable Pattern Internal Structure According to Role

REQ-PL-	029	Adaptable Pat According to R	tern internal structure Role
Description: In the process of pattern integration, the pattern internal structure must be available. The details of the pattern internal structure provided may vary according to the role of the person using the pattern.			
Source: General			
Reference process: Pattern Life cycle			
Rational: In order to ease the identification and selection of the pattern in the repository.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 07/06/10			Version: 1.0

5.2.1.9 Adaptable Pattern Internal Structure According to Level

REQ-PL-030 Adaptable Pattern internal structure According to Level			
Description: In the process of pattern integration, the pattern internal structure must be available. The details of the pattern internal structure provided may vary according to the level where the pattern is used.			
Source: General			
Reference process: Pattern Life cycle			
Rational: In order to ease the identification and selection of the pattern in the repository.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 07/06/10			Version: 1.0



5.2.1.10 Editable Domain Parameters

REQ-PL-031 Editable Domain Parameters

Description: The patterns can be used for different application sectors. It can also be implemented in different ways to improve the security, dependability, time of execution; etc. The parameters that can be useful for the pattern specialization must be provided. These parameters must be editable to support the variability of the pattern.

Source: General

Reference process: Pattern Life cycle

Rational: To identify the characteristics that allows the adaptation of the pattern in order to reach the desire functionality in different ways.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 27/05/10 **Version:** 1.0

5.2.1.11 Pattern Domain Dependent Information

REQ-PL-	032	Pattern Domaii	n dependent information
Description: In the event that the identified pattern is used primarily in a specific application domain, the application domain to which the pattern belongs must be specified.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: In the process of selecting the pattern, this domain dependent information helps the designer to decide the most appropriate pattern for the application.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 07/06/10			Version: 1.0



5.2.2 Editable Models

5.2.2.1 Pattern Search Mechanism (Level, Role)

REQ-PL-033	Pattern Search Mechanism (Level, Role)
Description: The patterns are stored in a repository of patterns. To access them, a mechanism to search the patterns must be provided. This mechanism can take into account certain search criteria that can simplify the search. Moreover, the information provided about the pattern can change depending on the level where the pattern is used and the role of the person involved with the pattern.	
Source: General	
Reference process: Pattern Lifecycle	

Rational: To ease the search of the patterns, and the interaction with the patterns.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 27/05/10 **Version:** 1.0

5.2.2.2 Description of Pattern Functionality

	· · · · · · · · · · · · · · · · · · ·			
REQ-PL-034		Description of pattern functionality		
Description: Once the artefacts for pattern description have been identified, and the strategies that have to be taken into account for pattern definition have been established, the pattern developer must specify the functionality, attributes and interfaces of the pattern.				
Source: General				
Reference process: Pattern Life cycle				
Rational: To identify the desired functionality to be achieved with the pattern.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 3	
Date: 06/10/10			Version: 1.0	



5.2.2.3 Pattern Description

	-		
REQ-PL-	035	Pattern Descrip	otion
Description: In the pattern definition process, a set of information (documents, diagrams, etc) to describe the pattern is generated. A mechanism to have the pattern description available must be provided.			
Source: General			
Reference process: Pattern Lifecycle			
Rational: To ease the organization and storing of the pattern description.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/05/10			Version: 1.0

5.2.2.4 Establish Dependency between Level Specific Views of Model

REQ-PL-	036	Establish Depe	endency between Specific odel
Description: The patterns can be used in different kinds of applications. These applications require that the pattern must be adapted. To support the correct use, instantiation and transformation of the patterns in the application, a relation between Specific views of the model (Level / Role Specific views) must be established.			
Source: General			
Reference process: Pattern Life cycle			
Rational: To guaranty that the pattern variability has been taken into account in the integration of the pattern in the application.			been taken into account in the
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 31/08/10			Version: 1.0



5.2.2.5 Pattern Characterization

Description: Once the parameters required for customizing the pattern have been identified, they must be accessible to customize the pattern for the application.

Source: General

Reference process: Pattern Life cycle

Rational: In the process of pattern characterization, a means that support the storage, access and manipulation of these parameters will allow an easy adaption of the pattern.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 27/05/10 **Version:** 1.0

5.2.2.6 Combining Patterns

REQ-PL-	038	Combining Pat	tterns
Description: In some applications, the functionality to be achieved can only be reached by grouping a number of patterns. The set of constraints and characteristics to take into account in the combination of the patterns must be provided.			
Source: General			
Reference process: Pattern Life cycle			
Rational: To consider all the characteristics in the pattern design process to support the composition of a number of patterns in an application.			
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/09/10			Version: 1.0



5.2.2.7 Identification of Pattern Interfaces

REQ-PL-039	Identification of pattern interfaces
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Description: In each application, the pattern must interact with other components or patterns. The interfaces of the pattern with the rest of the application must be provided.

Source: General

Reference process: Pattern Life cycle

Rational: To establish the way the pattern interacts with the rest of the components of the application (included other patterns).

Type: Optional Validation criteria: Inspection WP Relevance: 2

Date: 07/06/10 Version: 1.0

5.2.2.8 Substitute Pattern

REQ-PL-	040	Substitute Patt	ern
Description: Right now, the applications are used for different kind of products where some functionality can be affected. To support the change or adaption of this functionality in the application, the structure of the patterns must be defined as modular as possible in order to ease the replacement of the pattern.			
Source: General			
Reference process: Pattern Life cycle			
Rational: To ease the replacement of the pattern in the application.			
Type: Mandatory Validation criteria: Inspection WP Relevance: 2			WP Relevance: 2
Date: 01/09/10			Version: 1.0



5.2.3 Editable Transformations

5.2.3.1 Transformation Rules

REQ-PL-	041	Transformation	n Rules	
Description: In the pattern integration process, the pattern must be adapted to take into account the constraints of the application. The rules required to adapt / transform the pattern (interfaces, internal structure, etc) for the application must be available.				
Source: General				
Reference process: Pattern Life cycle				
Rational: To easy the pattern integration process.				
Type: Mandatory Validation criteria: Inspection WP Relevance: 2		WP Relevance: 2		
Date: 27/10/10			Version: 1.0	

5.2.3.2 Assistance / Guidelines for Easy Pattern Integration

REQ-PL-	1147	Assistance / Gintegration	uidelines for easy pattern
Description: Within the pattern integration process, a set of steps and restrictions has to be followed. Assistance in the pattern integration may be provided to carry out the actions related to this process.			
Source: Industrial Co	ontrol / Dependat	oility	
Reference process: Pattern Life cycle			
Rational: To ease the integration of the pattern in the application.			
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/05/10			Version: 1.0



5.2.3.3 Assurance of Pattern Dependency Consistency

REQ-PL-043	Assurance of pattern dependency consistency
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Description: In some cases, the patterns can be defined using some characteristics of other patterns in order to reduce the time to develop a new pattern and to avoid the introduction of a new source of errors in the new pattern. For that reason, when a pattern is deleted in the repository, all the dependencies with other patterns must be checked and replaced to avoid any undesired effect on the functionality of the others patterns in the repository.

Source: General

Reference process: Pattern Life cycle

Rational: Deleting a pattern must not compromise the consistency of the repository.

Type: Optional Validation criteria: Inspection WP Relevance: 2

Date: 03/06/10 **Version:** 1.0

5.2.3.4 Traceability of Properties during Pattern Life Cycle

REQ-PL-	044	Traceability of cycle	properties during pattern life	
Description: In the pattern design process, the properties that the pattern implements must be traced trough the pattern life cycle.				
Source: General				
Reference process: Pattern Lifecycle				
Rational: To trace the properties implementation throughout the pattern definition.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 3	
Date: 27/05/10	,		Version: 1.0	



5.2.3.5 Repository - Pattern Validation

REQ-PI	₋ -045	Repository - I	Pattern validation	
Description: Any pattern (whether new or modified) that is added to the repository must be validated according to the S&D validation method / approach associated with the pattern. The patterns provided in the repository are validated.				
Source: General				
Reference process: Pattern Life cycle				
Rational: To avoid the introduction of S&D lacks in the patterns added to the repository.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2, 3	
Date: 03/06/10	-1		Version: 1.0	



6 Requirements on Integration Process Transformations

In this section, we will identify and detail all requirements related to the integration process. This section is divided in two subsections. The first one, called "Domain Independent Pattern Integration", is relevant for the task 3.1 and represents a part of the deliverable D3.1. The second one, titled "Domain Specific Pattern Integration" corresponds to the deliverable D2.2.

6.1 Domain Independent Pattern Integration

6.1.1 Conceptual level

6.1.1.1 Pattern Selection / Discrimination

REQ-IPT-	-001	Pattern selection	on / discrimination			
Description: Some information (i.e., properties, interfaces, etc) has been defined to provide a complete description of the pattern. This information must be available for the pattern user to select the appropriated pattern for the application.						
Source: General						
Reference process:	Domain Indeper	ndent Pattern Inte	egration process			
	Rational: The information about the pattern description must be available to ease the selection of the pattern for the application developer.					
Type: Mandatory Validation criteria: Inspection WP Relevance: 3						
Date: 07/06/10			Version: 1.0			

6.1.1.2 Integration - Pattern Validation

REQ-IPT-	REQ-IPT-002 Integration - pattern validation				
Description: Once the pattern has been integrated in the application, it must be guaranteed that the features provided by the integrated pattern (e.g. S&D properties) have been validated and that the pattern has been properly integrated in the application.					
Source: General					
Reference process:	Domain Indeper	ndent Pattern Int	egration process		
Rational: To prove that the integration of the pattern in the application have been performed properly.					
Type: Mandatory Validation criteria: Inspection WP Relevance: 3			WP Relevance: 3		
Date: 27/05/10			Version: 1.0		



6.1.1.3 Traceability of S&D Requirements During Pattern Integration

REQ-IPT-	-003	Traceability of pattern integra	S&D requirements during ation		
Description: Before integrating a pattern in a specific application, some S&D requirements have been defined. These requirements are met by the patterns and must be traced through the integration, verification, and validation of the pattern in the application.					
Source: General					
Reference process:	Domain Indeper	ndent Pattern Int	egration process		
Rational: To trace the S&D requirements in the application					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 3		
Date: 27/05/10			Version: 1.0		

6.1.2 Modelling

6.1.2.1 Specifying S&D Integration Requirement

onizir opeanymg daz magration requirement					
REQ-IPT-004 S&D integration requirements definition					
Description: There are some specific constraints against the application e.g. environmental constraints which must be taken into account in the process of integration of the pattern in a specific application. With this information, the S&D integration requirements must be defined in such ways that they are precise, clear and easy to understand.					
Source: General					
Reference process:	Domain Indeper	dent Pattern Int	egration process		
Rational: To identify the requirements to fulfil for the integration of the pattern in the application and also to easily understand the meaning of the S&D integration requirements.					
Type: Mandatory Validation criteria: Inspection WP Relevance: 3					
Date: 27/05/10			Version: 1.0		



6.1.2.2 Determination of the User's System Model

REQ-IPT-005

Determination of the user's system model

Description: For a successful pattern integration in the user's system or application it is necessary to take into account several information about the user's system model in order to validate if the provided pattern functionality has been reached. For instance this includes system components and their interfaces, S&D objectives, and S&D threats that needs to be handled. The user should be leaded by a list of questions to specify these properties. The questionnaire should be context sensitive and should make suggestions (e.g., Did you think of threat XY? Is that relevant for you?). It should collect information in a structured, iterative process:

- 1. Actors/roles
- 2. Data/interfaces
- 3. Functions/use cases
- 4. Security assets
- 5. Potential attackers
- 6. Potential threats
- 7. Misuse cases
- 8. Security environment
- 9. Attacker model
- 10. Attack paths
- 11. Attack potentials
- 12. Potential damages
- 13. Risk evaluation
- 14. Necessary security functionality
- 15. Security properties

and finally lead to a solution, i.e., preliminary selection of patterns relevant for the user's problem.

Source: General

Reference process: Domain Independent Pattern Integration

Rational: To easily determine an extensive, unambiguous view of the user's system model that allows validating the pattern integration and furthermore can be used to improve the efficiency of the pattern search process, i.e., automatically make a preliminary selection of patterns relevant for the user's problem.

Type: Mandatory Validation criteria: Inspection WP Relevance: 3

Date: 09/11/2010 Version: 1.0



6.1.3 Transformation

6.1.3.1 Guidelines for Easy Pattern Integration (Domain Independent Actions)

REQ-IPT-	REQ-IPT-006 Guidelines for easy pattern integration (domain independent actions)					
-	Description: The set of domain independent actions (procedures) required for integrating the pattern in an application must be defined.					
Source: General						
Reference process:	Domain Indeper	dent Patteri	n Integra	tion process		
Rational: To reduce t	the complexity of	the integrat	on of the	e pattern in the	applicatio	n.
Type: Mandatory Validation criteria: Inspection WP Relevance: 3						
Date: 27/05/10			Vers	sion: 1.0		

6.1.3.2 Match the Interfaces between the Pattern and the Application

REQ-IPT-	_/	Match the inte	erfaces between the pattern and n		
Description: In the process of integrating the pattern into the application, the interfaces between the application and the pattern must be analyzed and adapted in order to get a correct integration.					
Source: General					
Reference process:	Domain Indeper	ndent Pattern Ir	tegration process		
Rational: To get a co	Rational: To get a correct interaction between the pattern and the application				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 3		
Date: 23/08/10	•		Version: 1.0		



6.1.3.3 Consistency between Domain Independent and Domain Specific Models

REQ-IPT-	Consistency between domain independent and domain specific models				
Description: During the pattern integration process, transformations are required to take into account some domain specific capabilities and constraints. The pattern user must guarantee consistency between these transformations during pattern integration.					
Source: General					
Reference process:	Domain Indeper	ndent Pattern Int	egration process		
Rational: To guarantee the correct transformation of the pattern into the pattern integration process.					
Type: Mandatory	Validation crite	eria: Inspection	WP Relevance: 3		
Date: 27/09/10			Version: 1.0		

6.2 Domain Specific Pattern Integration

6.2.1 Editable Conceptual Level

6.2.1.1 Project's Organizational Model

REQ-IPT-009 Project's organizational model					
Description: The process should provide the information (documentation) related to the pattern following the organizational model (based on standards such as ISO 9000-1) defined for the specific project.					
Source: General					
Reference process:	Domain Specific F	Pattern Integrati	on process		
Rational: To guarantee quality assurance					
Type: Optional Validation criteria: Inspection WP Relevance: 2					
Date: 27/05/10			Version: 1.0		



6.2.1.2 Specialization of Artefact Instances

REQ-IPT	-010	Specialization	of artefa	act instanc	es	
Description: The process must provide a mechanism to specialize the artefact instances for domain specific needs.						
Source: General						
Reference process:	Domain Specific	Pattern Integra	tion proc	ess		
Rational: To characte	erize the artefact	s to the domain	specific	needs.		
Type: Mandatory Validation criteria: Inspection WP Relevance: 2						
Date: 27/05/10			Version	n: 1.0		

6.2.2 Editable Modelling

6.2.2.1 Using Coding Standards

REQ-IPT-	-011	Using coding s	ng standards			
<u>-</u>	Description: In the implementation of the pattern, the process should generate the pattern code following the strict syntactic coding rules defined for the application.					
Source: General						
Reference process:	Domain Specific	Pattern Integration	on process			
Rational: To respect	quality restriction	าร				
Type: Optional Validation criteria: Analysis WP Relevance: 2			WP Relevance: 2			
Date: 27/05/10		Version: 1.0				



6.2.2.2 Adaptation of Pattern to Resource Constraints

REQ-IPT-	-012	Adaptation of p	pattern to resource constraints		
Description: The actions related to the pattern's integration into the application are linked to a set of transformations in order to consider several constraints in its use. The process must consider the resource constraints during the pattern adaptation.					
Source: General					
Reference process:	Domain Specific	Pattern Integrat	ion process		
Rational: To take into integration process	account the sys	stem resource co	onstraints in the pattern		
Type: Mandatory Validation criteria: Inspection WP Relevance: 2					
Date: 07/10/10			Version: 1.0		

6.2.3 Editable Transformations

6.2.3.1 Guidelines for Easy Pattern Integration (Domain Specific Actions)

REQ-IPT-	_/ /	Guidelines for (domain specif	easy pattern integration ic actions)		
	Description: The set of domain specific actions (procedures) required for integrating the pattern in a specific project must be defined.				
Source: General					
Reference process:	Domain Specific	Pattern Integrat	ion process		
Rational: To ease the in the pattern integrat		nd implementation	n of the domain specific actions		
Type: Mandatory Validation criteria: Inspection WP Relevance: 2			WP Relevance: 2		
Date: 07/06/10			Version: 1.0		

Adaptation of pattern to domain specific



6.2.3.2 Adaptation of Pattern to Domain Specific Constraints

Description: The actions related to the pattern's integration into the application are linked to a set of transformations in order to consider several constraints in its use. The process must consider the domain specific constraints during the pattern adaptation.

Source: General

Reference process: Domain Specific Pattern Integration process

Detional. To take into account the alamain and its account in the man

Rational: To take into accounts the domain specific constraints in the pattern integration process.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 07/10/10 **Version:** 1.0

6.2.3.3 Certification

REQ-IPT-	-015	Certification		
Description: Where certification criterion.	Description: Where necessary, the formal validation must follow a domain specific certification criterion.			
Source: General				
Reference process:	Formal Validatio	n Process		
	Rational: To take into account specific criteria in the application domains that can be relevant in the validation process.			
Type: Optional Validation criteria: Inspection WP Relevance: 2			WP Relevance: 2	
Date: 27/05/10		Version: 1.0		



6.2.3.4 Integration of the Formal Validation

REQ-IPT-016 Integration of the formal validation

Description: Once the formal validation of the application has been performed, the results of this evaluation have to be available in order to analyze them. For that reason, the results of the formal validation must be distributed to the participants of the project in a format consistent with the engineering process.

Source: General

Reference process: Formal Validation Process

Rational: The pattern repository and integration process must foresee possibilities to

inspect the S&D proof.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 27/05/10 **Version:** 1.0



7 Requirements on Repository Structure

In this section, we will identify and detail all requirements related to the repository structure. This section is divided in two subsections. The first one, called "Conceptual Level", is relevant for the task 4.1 and represents a part of the deliverable D4.1. The second one, titled "Modelling Level" corresponds to the deliverable D2.2.

7.1 Conceptual Level

7.1.1 Artefacts

7.1.1.1 Domain Independent Repository Construction

REQ-RS-	001	Domain indepe	endent repository construction		
	Description: The repository must support the acquisition and categorization of the set of domain independent artefacts required for the repository construction.				
Source: General					
Reference process:	Repository Struc	cture			
	Rational: To have all the required domain independent artefacts identified for pattern implementation in the repository.				
Type: Mandatory Validation criteria: Inspection			WP Relevance: 4		
Date: 07/06/10			Version: 1.0		

7.1.1.2 Domain Specific Repository Construction

REQ-RS-	·002	Domain specifi	ic repository construction		
· ·	Description: The repository must support the acquisition and categorization of the set of domain specific artefacts required for the repository construction.				
Source: General					
Reference process:	Repository Struc	cture			
	Rational: To have all the required domain specific artefacts identified for pattern implementation in the repository.				
Type: Mandatory Validation criteria: Inspection			WP Relevance: 4		
Date: 07/06/10		Version: 1.0			



7.1.1.3 Domain Independent Repository Organization

REQ-RS-	-003	Domain indepe	endent repository organization		
•	Description: The repository must support the acquisition and categorization of the set of domain independent artefacts required for the repository organization.				
Source: General					
Reference process:	Repository Struc	cture			
Rational: To have all indexing.	Rational: To have all the required domain independent artefacts for the patterns indexing.				
Type: Mandatory Validation criteria: Inspection			WP Relevance: 4		
Date: 07/06/10			Version: 1.0		

7.1.1.4 Domain Specific Repository Organization

REQ-RS-	-004	Domain specifi	ic repository organization			
-	Description: The repository must support the acquisition and categorization of the set of domain specific artefacts required for the repository organization.					
Source: General						
Reference process:	Repository Struc	cture				
Rational: To have al	Rational: To have all the required domain specific artefacts for the patterns indexing.					
Type: Mandatory Validation criteria: Inspection			WP Relevance: 4			
Date: 07/06/10			Version: 1.0			



7.1.1.5 Domain Independent Pattern Retrieval

REQ-RS-	-005	Domain indepe	endent patterns retrieval			
Description: The repository must support the acquisition and categorization of the set of domain independent artefacts which are required for the implementation of the patterns retrieval policies (i.e., techniques of searching and selection of patterns).						
Source: General	Source: General					
Reference process:	Reference process: Repository Structure					
Rational: To have all the required domain independent tools which mechanize the identification process.						
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4			

Date: 07/06/10 **Version**: 1.0

7.1.1.6 Domain Specific Patterns Retrieval

REQ-RS-	-006	Domain specifi	ic patterns retrieval	
Description: The repository must support the acquisition and categorization of the set of domain specific artefacts required for the implementation of the patterns retrieval policies.				
Source: General				
Reference process:	Repository Struc	cture		
Rational: To have all the required domain specific artefacts which mechanize the identification process.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4	
Date: 07/06/10		Version: 1.0		



7.1.1.7 Visualisation of a Pattern

REQ-RS	-007	Visualisation o	f a pattern		
•	Description: The repository must support the acquisition and categorization of the set of graphical artefacts required for the visualisation of a pattern				
Source: General					
Reference process:	Repository Struc	cture			
Rational: To have al in the repository.	Rational: To have all the required graphical artefacts identified for pattern visualisation in the repository.				
Type: Mandatory Validation criteria: Inspection		WP Relevance: 4			
Date: 28/10/10			Version: 1.0		

7.1.1.8 Role Dependent Visualisation of the Repository

REQ-RS-	009	Role Depender Repository	nt Visualisation of the		
•	Description: The repository can be viewed in accordance to the role of the user. Its role specific representation must be used.				
Source: General					
Reference process:	Repository Struc	cture			
	Rational: To have all the required graphical artefacts identified for the visualisation of the repository according to the role user.				
Type: Mandatory Validation criteria: Inspection			WP Relevance: 4		
Date: 28/10/10		Version: 1.0			



7.1.2 Modelling

7.1.2.1 Guidelines on Interactions with the Repository

REQ-RS-	·010	Guidelines for repository	an easy interaction with the		
-	Description: The set of domain specific actions (procedures) required to interact with the repository must be defined. The process must provide guidelines.				
Source: General					
Reference process:	Repository Struc	cture			
Rational: To ease the	Rational: To ease the use of the repository.				
Type: Mandatory Validation criteria: Inspection WP Relevance: 4			WP Relevance: 4		
Date: 07/07/10		Version: 1.0			

7.1.2.2 Multiview Support for Domain and Actor Specific Adaptation

REQ-RS	-011	Multiview suppospecific adapt	port for domain and actor ation	
Description: Depending on the application domain, a pattern can be implemented through different ways according to specific concern focuses. For this purpose, the process has to support different views of the pattern depending on the role of the pattern developer or user.				
Source: General				
Reference process:	Repository Struc	cture		
Rational: To ease the interaction and the understanding of the pattern for different stakeholders of the project.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4	
Date: 07/06/10	1		Version: 1.0	



Date: 27/05/10

7.1.2.3 Repository Compliant Description of the Pattern

REQ-RS-	014	Repository cor pattern	mpliant description of the	
Description: The repository must provide a mechanism to collect and separate all the information generated throughout the pattern definition and generation. Moreover the repository must support the extended information generated through the adaptation of the pattern to the application and provide this information with existent information of the pattern. Source: General				
Reference process: Repository Structure				
Rational: To ease organization of the pattern information and to increase the understanding of the pattern.				
Type: Mandatory	Validation crite	eria: Inspection	WP Relevance: 4	

Version: 1.0

7.1.2.4 Domain and Role Based Pattern Searching

		_		
REQ-RS-	015	Domain and ro	le based pattern searching	
Description: The patterns may have different ways of implementation, or their use may be focused on certain phases of application design where only a few roles can work with this. This information can be used to easy the search for patterns in the repository. The pattern search mechanism of the process should take into account the application domain where the pattern is used and the actors to which the pattern is in focus.				
Source: General				
Reference process: Repository Structure				
Rational: To ease the search of the pattern in the repository.				
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4	
Date : 27/05/10		Version: 1.0		



Date: 27/05/10

7.1.2.5 Support Dependencies between Patterns

REQ-RS-	016	Support depen	dencies between patterns
Description: In order to reduce the pattern development time and to reduce the source of errors in the pattern definition, the repository must provide functionalities that allow the pattern designer to create new dependencies between patterns and to easy the interaction with the existent ones.			
Source: General			
Reference process: Repository Structure			
Rational: To ease the definition of new patterns.			
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4

Version: 1.0

7.1.2.6 Guideline for Defining Pattern Dependencies

REQ-RS-	-017	Guideline for d	lefining pattern dependencies	
Description: Generating/ Adding a pattern in the repository sometimes requires the use of an existing pattern stored in the repository. For that reason new dependencies have to be generated to establish the relation between these patterns. The repository must provide a guideline to define the new dependencies and the way to add them in the repository.				
Source: General				
Reference process: Repository Structure				
Rational: To ease the definition of new dependencies in the repository.				
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4	
Date : 27/05/10			Version: 1.0	



7.1.2.7 Support the Visualisation of the Pattern Dependencies

REQ-RS-	019	Visualisation o	f the pattern dependencies
Description: The repository must provide the possibility to visualise a graph of pattern dependencies.			ity to visualise a graph of pattern
Source: General			
Reference process:	Repository Struc	cture	
Rational: To ease the pattern and all the oth		•	that exist between a given trom itself.
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4
Date: 28/10/10	1		Version: 1.0

7.1.3 Transformation

7.1.3.1 Adaptation of the visualisation according to the user role

REQ-RS-	-021	Adaptation of t	the visualisation according to
Description: In the repository, a pattern can be viewed in accordance the concern of the pattern user. The visualisation of the pattern should be adapted according to the user role. A tool must implement this function.			
Source: General			
Reference process:	Repository Struc	cture	
Rational: To ease the	e selection and ເ	inderstanding of	the pattern.
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4
Date: 28/10/10	ı		Version: 1.0



7.1.3.2 Data Structure to Implement the Repository

REQ-RS-	022	Data structure	to implement the Repository
Description: The data structure that implement the repository internal structure must be chosen by taking into account the following elements: Visualisation – Modules of interaction – Repository Internal Structure			
Source: General			
Reference process: Repository Structure			
Rational: To identify the main elements to consider in the definition of the repository internal structure and subsequently to ease the search of the pattern in the repository.			
Type: Optional	Validation crite	ria: Inspection	WP Relevance: 4
Date: 28/10/10	1		Version: 1.0

7.2 Modelling Level

7.2.1 Editable Artefacts

7.2.1.1 Edit Repository Search Keys

REQ-RS-	-023	Edit Repositor	y Search Keys
Description: The repository must support the definition of keywords that support the search for a specific pattern.			
Source: General			
Reference process: Repository structure			
Rational: To ease the	e search for patte	erns.	
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 27/05/10	,		Version: 1.0



7.2.1.2 Edit Visualisation of a Pattern

REQ-RS-	024	Edit Visualisati	ion of a pattern	
•	Description: The repository must support the definition of artefacts that can help in the visualisation of the pattern.			
Source: General				
Reference process: Repository structure				
Rational: To ease the visualisation of the patterns.				
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2	
Date: 28/10/10			Version: 1.0	

7.2.1.3 Edit Visualisation of a Pattern Dependencies

REQ-RS-	025	Edit Visu depende		on of the pattern
Description: The repository must support the definition of artefacts that can help in the visualisation of the pattern dependencies.				
Source: General				
Reference process:	Repository struc	cture		
Rational: To ease the	e visualisation of	the patter	n depe	endencies.
Type: Mandatory	Validation crite	ria: Inspe	ction	WP Relevance: 2
Date: 28/10/10				Version: 1.0



7.2.1.4 Edit User Role View

REQ-RS-	-026	Edit User Role	View
Description: The user role view can be modified.			
Source: General			
Reference process: Repository structure			
Rational: To adapt the visualisation to new needs.			
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2
Date: 28/10/10		Version: 1.0	

7.2.2 Editable Models

7.2.2.1 Support Pattern Search Function According to Level

		_	
REQ-RS-	-027	Support Patter to level	rn Search Function according
Description: In some situations, it is necessary to look for a pattern already defined in the repository in order to carry out an action on it, e.g. modification/correction on an existing pattern. The process must provide a function to search the pattern in the repository according to a level.			
Source: General			
Reference process: Repository structure			
Rational: To ease the	e search of the p	atterns.	
Type: Mandatory	Validation crite	eria: Inspection	WP Relevance: 2
Date : 27/05/10	I		Version: 1.0



7.2.2.2 Support Pattern Search Function According to Role

RECIERSION	Support Pattern Search Function according to Role
n: In some situations, it is i	necessary to look for a pattern already defined in

Description: In some situations, it is necessary to look for a pattern already defined in the repository in order to carry out an action on it, e.g. modification/correction on an existing pattern. The process must provide a function to search the pattern in the repository according to a role.

Source: General

Date: 28/10/10

Reference process: Repository structure

Rational: To ease the search of the patterns.

Type: Mandatory Validation criteria: Inspection WP Relevance: 2

Date: 27/05/10 **Version:** 1.0

7.2.2.3 Edit the Functionality Relating the Visualisation of a Pattern

REQ-RS-	029	Edit the function of a pattern	onality relating the visualisation			
Description: The pattern user can use the functionality relating the visualisation of a pattern in order to understand its meaning. In addition, this functionality can be used in collaboration with the functionality concerning the pattern search. Indeed, depending of the user analyse, he can decide to keep this pattern or to search another (in the case where the present pattern does not meet his requirement).						
Source: General						
Reference process: Repository Structure						
Rational: To ease the selection of a pattern.						
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 4			

Version: 1.0



7.2.2.4 Edit the Functionality Relating the Visualisation of the Pattern Dependencies

REQ-RS-	·030	Edit the function of the pattern	onality relating the visualisation dependencies		
Description: The pattern user can use the functionality relating the visualisation of the pattern dependencies in order to see a part of the complexity of the pattern (complexity in term of dependencies). Once the pattern user knows this complexity, he can decide to use the pattern or to search another one.					
Source: General					
Reference process: Repository Structure					
Rational: To ease the selection of a pattern.					
Type: Mandatory	Validation crite	ria: Inspection	WP Relevance: 2		
Date: 28/10/10	,		Version: 1.0		

7.2.3 Editable Transformations

7.2.3.1 Edit the Data Structure to Implement the Repository

REQ-RS-	·033	Edit data struct	ture to implement the		
Description: The repository must support the definition of artefacts that can help to create the repository implementation					
Source: General					
Reference process: Repository structure					
Rational: To ease the repository implementation					
Type: Mandatory	Validation crite	eria: Inspection	WP Relevance: 2		
Date: 28/10/10			Version: 1.0		



8 Conclusion

This document represents the deliverables D2.2, D3.1 & D4.1 which address requirements. The list of the requirements and their description represents our current understanding of the TERESA scope. This document will be modified during the project in order to meet our new needs.

This document represents an entry point for other tasks and deliverables such as D3.2 and D4.2. A state of the art on related work will be done in the next deliverables in order to highlight the TERESA contributions and how the requirements of the present document will be take into account and use in the TERESA project.



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